

Electronic Supplementary Information

Oxalic acid photooxidation on rutile nanowire electrodes

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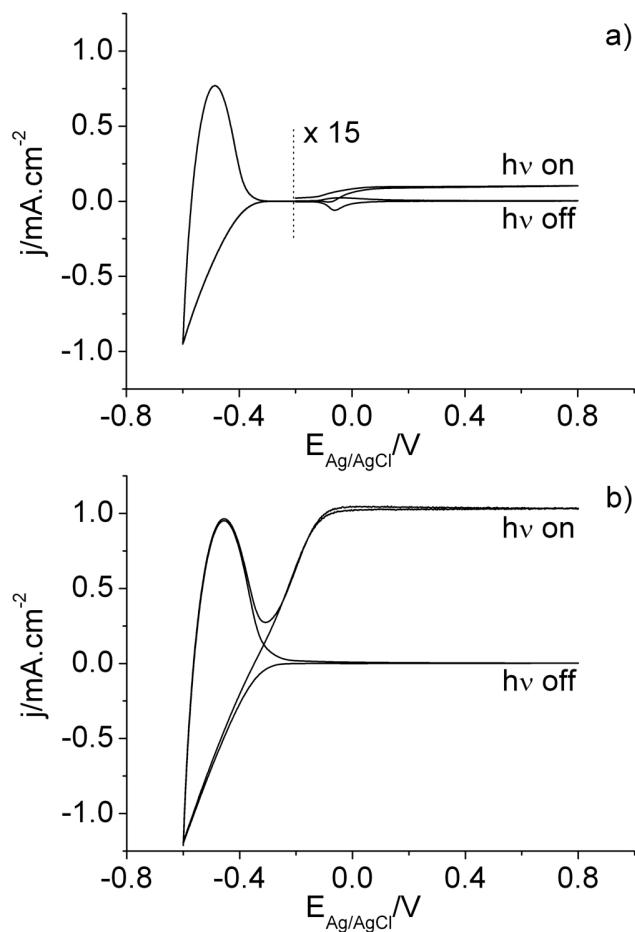


Figure S1. Voltammograms of a NW-TiO₂@FTO electrode in a 100 mM HClO₄ aqueous solution (a) and in a 50 mM H₂C₂O₄ + 100 mM HClO₄ aqueous solution (b) in the dark and during UV/Vis exposure. Polychromatic EE illumination; 300 W Xe lamp; I(E < 6.2 eV) = 500 mW·cm⁻²; scan rate: 20 mV·s⁻¹; film thickness: d(TiO₂) = 360 nm.

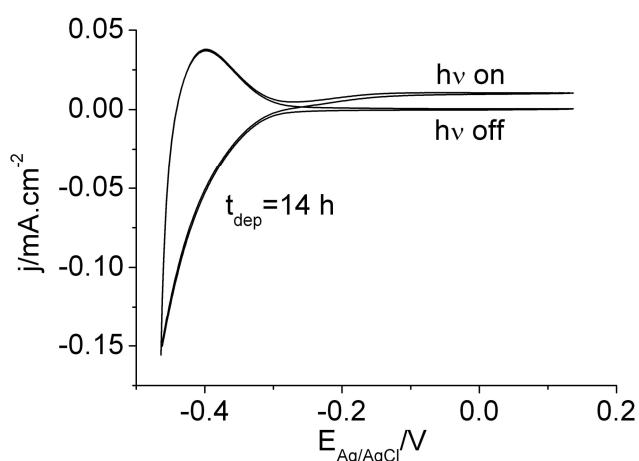


Figure S2. Voltammograms of a NW-TiO₂@Au@Si thin film (oxide deposition time: 14 h) in 10 mM H₂C₂O₄ + 100 mM HClO₄ aqueous solution in the dark and during UV/Vis exposure; polychromatic EE illumination; 50 W medium-pressure Hg lamp, $I = 10 \text{ mW}\cdot\text{cm}^{-2}$; scan rate: 20 $\text{mV}\cdot\text{s}^{-1}$.